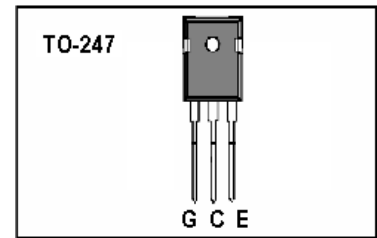
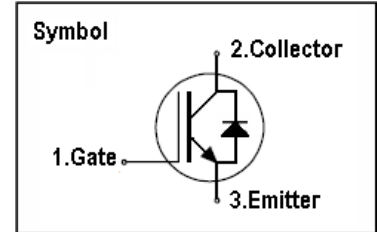


## IGBT

### Features

- 1200V,25A
- $V_{CE(sat)(typ.)}=2.2V@V_{GE}=15V,I_C=25A$
- High speed switching
- Higher system efficiency
- Soft current turn-off waveforms
- Square RBSOA using NPT technology



### General Description

JIAEN NPT IGBTs offer lower losses and higher energy efficiency for application such as IH (induction heating), UPS, general inverter and other soft switching applications.

### Absolute Maximum Ratings

Symbol	Parameter	Value	Units
$V_{CES}$	Collector-Emitter Voltage	1200	V
$V_{GES}$	Gate-Emitter Voltage	$\pm 30$	V
$I_C$	Continuous Collector Current ( $T_C=25^\circ C$ )	45	A
	Continuous Collector Current ( $T_C=100^\circ C$ )	25	A
$I_{CM}$	Pulsed Collector Current (Note 1)	80	A
$I_F$	Diode Continuous Forward Current ( $T_C=100^\circ C$ )	25	A
$I_{FM}$	Diode Maximum Forward Current (Note 1)	60	A
$t_{sc}$	Short Circuit Withstand Time	10	us
$P_D$	Maximum Power Dissipation ( $T_C=25^\circ C$ )	220	W
	Maximum Power Dissipation ( $T_C=100^\circ C$ )	100	W
$T_J$	Operating Junction Temperature Range	-55 to +150	$^\circ C$
$T_{STG}$	Storage Temperature Range	-55 to +150	$^\circ C$

### Thermal Characteristics

Symbol	Parameter	Max.	Units
$R_{th\ j-c}$	Thermal Resistance, Junction to case for IGBT	0.45	$^\circ C/W$
$R_{th\ j-c}$	Thermal Resistance, Junction to case for Diode	0.85	$^\circ C/W$
$R_{th\ j-a}$	Thermal Resistance, Junction to Ambient	40	$^\circ C/W$

**Electrical Characteristics** ( $T_C=25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$BV_{CES}$	Collector-Emitter Breakdown Voltage	$V_{GE}=0V, I_C=250\mu A$	1200	-	-	V
$I_{CES}$	Collector-Emitter Leakage Current	$V_{CE}=1200V, V_{GE}=0V$	-	-	250	$\mu A$
$I_{GES}$	Gate Leakage Current, Forward	$V_{GE}=30V, V_{CE}=0V$	-	-	100	nA
	Gate Leakage Current, Reverse	$V_{GE}=-30V, V_{CE}=0V$	-	-	-100	nA
$V_{GE(th)}$	Gate Threshold Voltage	$V_{GE}=V_{CE}, I_C=250\mu A$	4.5	-5.0	5.5	V
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	$V_{GE}=15V, I_C=25A$	-	2.2	2.5	V
$Q_g$	Total Gate Charge	$V_{CC}=960V$ $V_{GE}=15V$ $I_C=25A$	-	130		nC
$Q_{ge}$	Gate-Emitter Charge		-	30		nC
$Q_{gc}$	Gate-Collector Charge		-	70		nC
$t_{d(on)}$	Turn-on Delay Time	$V_{CC}=600V$ $V_{GE}=15V$ $I_C=25A$ $R_G=10\Omega$ Inductive Load $T_C=25^\circ\text{C}$	-	22	-	ns
$t_r$	Turn-on Rise Time		-	35	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	290	-	ns
$t_f$	Turn-off Fall Time		-	170	-	ns
$E_{on}$	Turn-on Switching Loss		-	2.2	-	mJ
$E_{off}$	Turn-off Switching Loss		-	1.4	-	mJ
$E_{ts}$	Total Switching Loss		-	3.6	-	mJ
$C_{ies}$	Input Capacitance	$V_{CE}=25V$ $V_{GE}=0V$ $f=1\text{MHz}$	-	1250	-	pF
$C_{oes}$	Output Capacitance		-	210	-	pF
$C_{res}$	Reverse Transfer Capacitance		-	150	-	pF
$R_{gint}$	Integrated gate resistor			3.8		$\Omega$

**Electrical Characteristics of Diode** ( $T_C=25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_F$	Diode Forward Voltage	$I_F=25A$	-	2.3	2.5	V
$t_{rr}$	Diode Reverse Recovery Time	$V_{CE}=600V$	-	190		ns
$I_{rr}$	Diode peak Reverse Recovery Current	$I_F=25A$	-	20		A
$Q_{rr}$	Diode Reverse Recovery Charge	$dI_F/dt=500A/\mu s$	-	1600		nC

**Notes:**

1. Repetitive Rating: Pulse width limited by maximum junction temperature

**Typical Performance Characteristics**

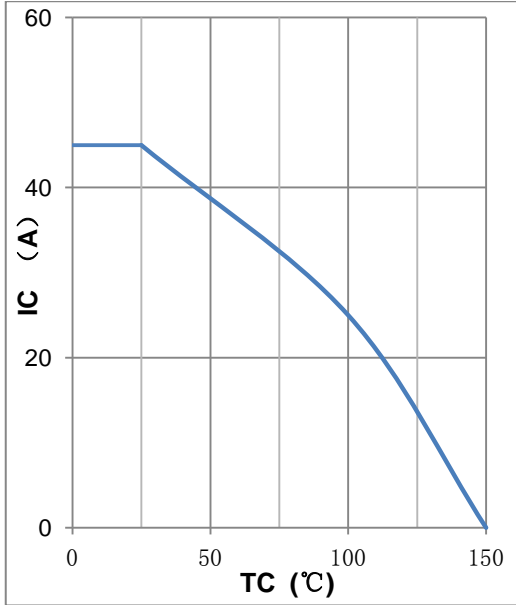


Figure1:maximum DC collector current VS. case temperature

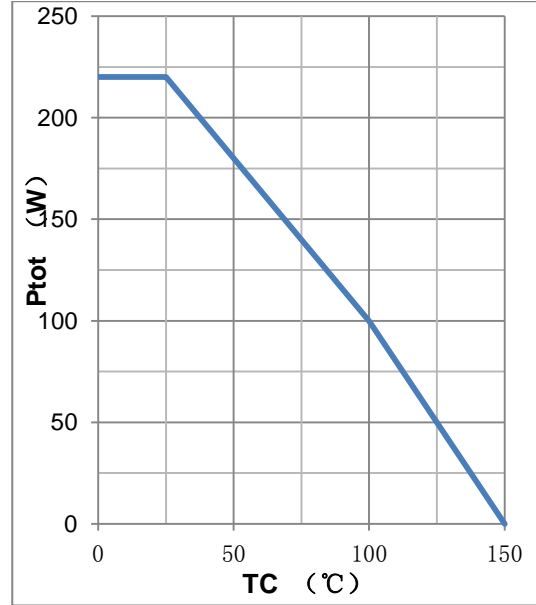


Figure2:power dissipation VS. case temperature

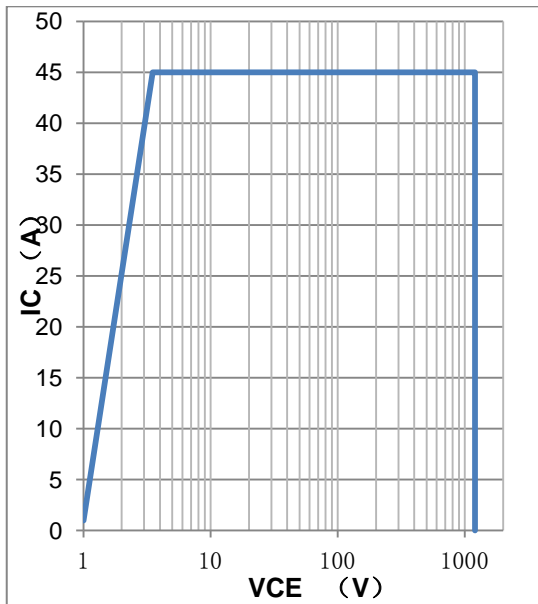


Figure3:reverse bias SOA,TJ=150°C,VGE=15V

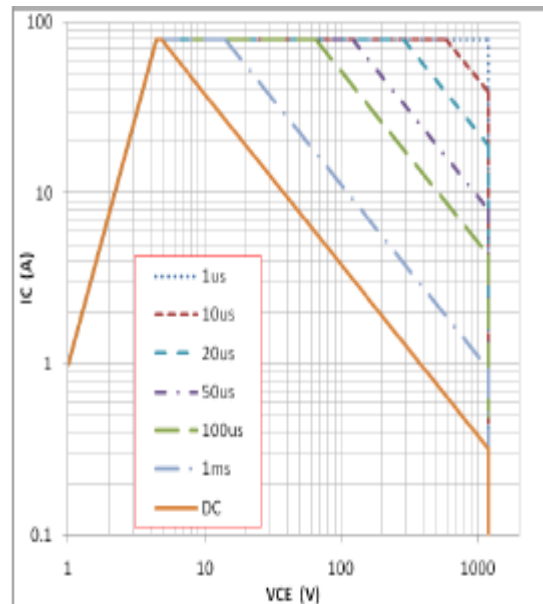


Figure4:forward SOA,TC=25°C,TJ ≤ 150°C

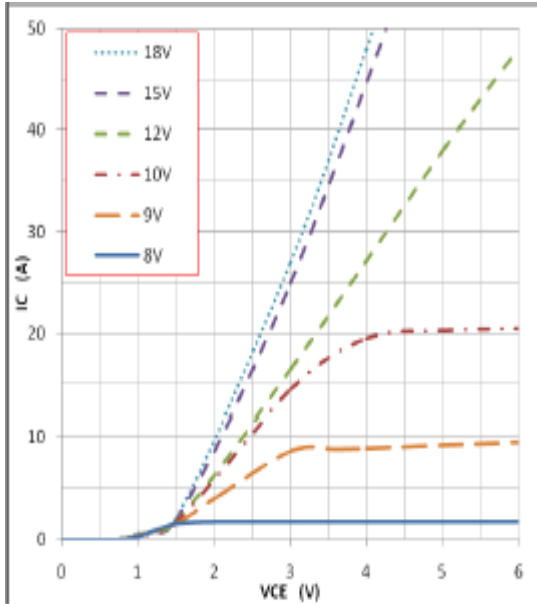


Figure5:typical IGBT output characteristics,  
 $T_J=25^{\circ}\text{C};t_p=300\mu\text{s}$

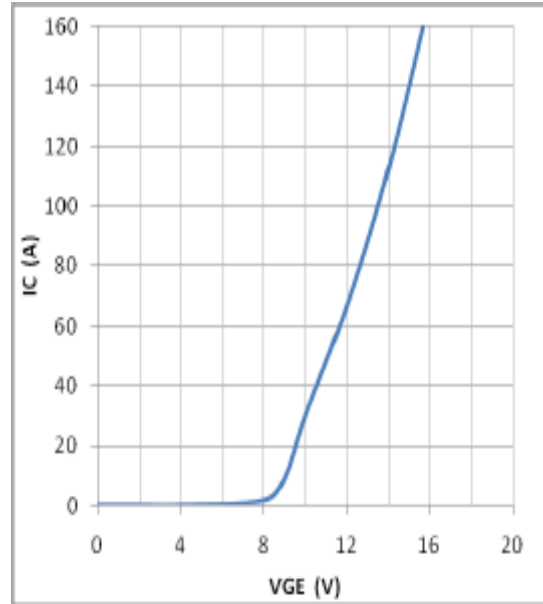


Figure6:typical trans characteristics, $V_{CE}=20\text{V},t_p=20\mu\text{s}$

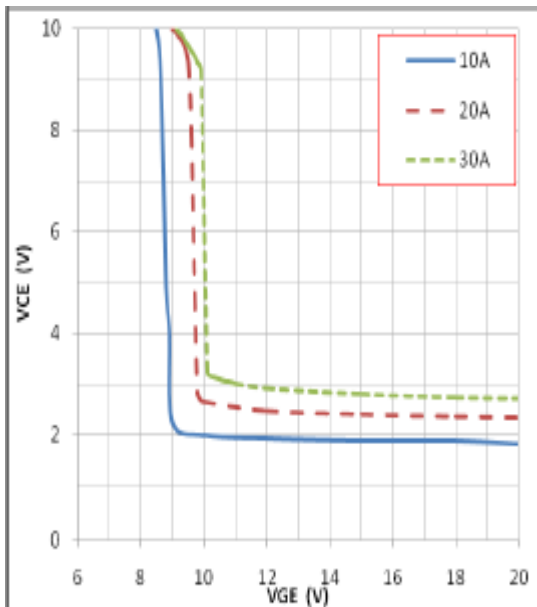


Figure7: typical  $V_{CE}$  VS.  $V_{GE}$ , $T_J=25^{\circ}\text{C}$

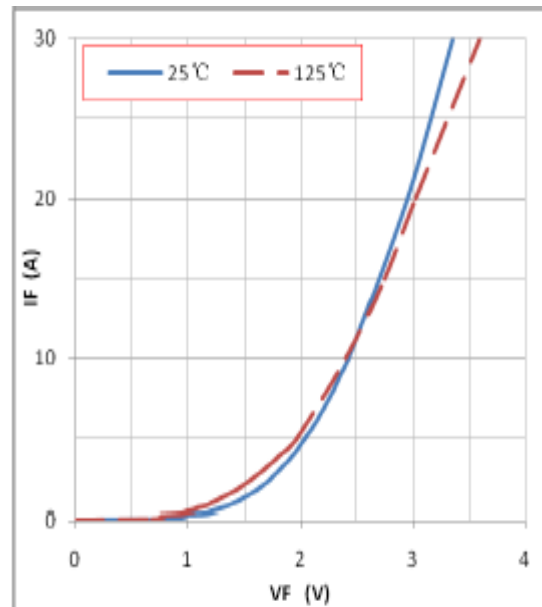


Figure8:typical diode forward characteristic, $t_p=300\mu\text{s}$

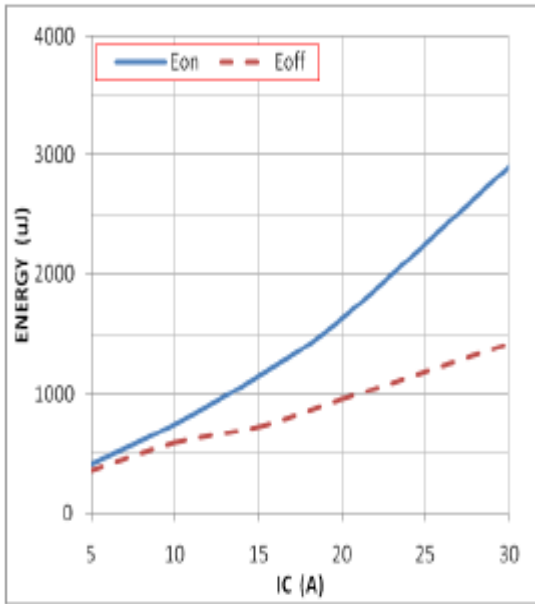


Figure9: typical energy loss VS. IC, TC=25°C,  
L=500uH, VCE=600V, VGE=15V, Rg=28Ω

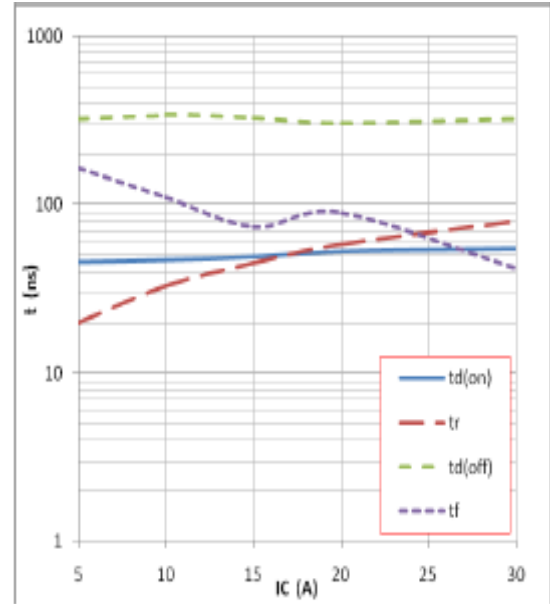


Figure10: typical switching time VS. IC, TC=25°C,  
L=500uH, VCE=600V, VGE=15V, Rg=28Ω

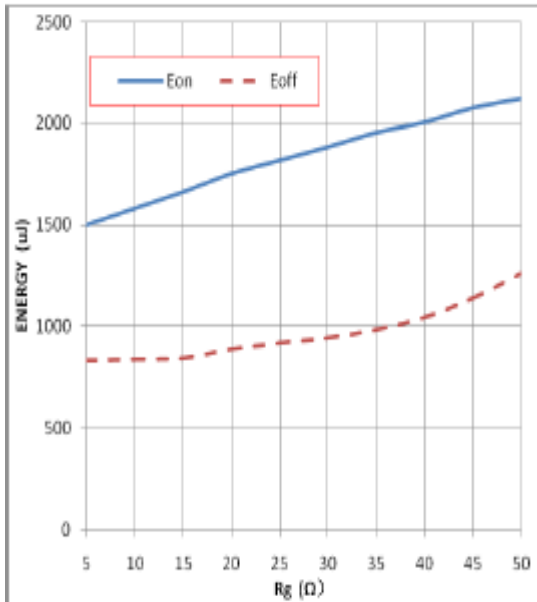


Figure11: typical energy loss VS. Rg, TC=25°C,  
L=500uH, VCE=600V, VGE=15V, IC=25A

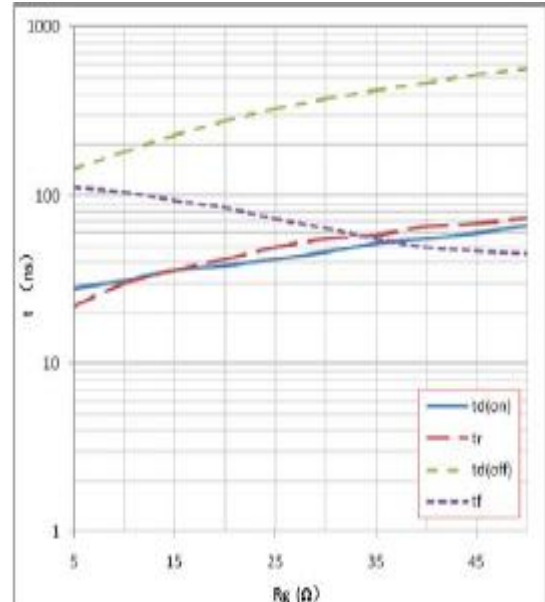


Figure12: typical switching time VS. Rg, TC=25°C,  
L=500uH, VCE=600V, VGE=15V, IC=25A

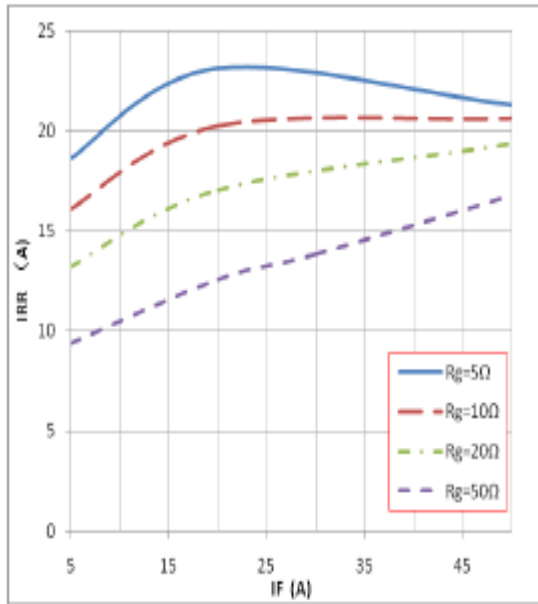


Figure13: typical diode IRR VS. IF, TC=25°C  
VCC=600V, VGE=15V

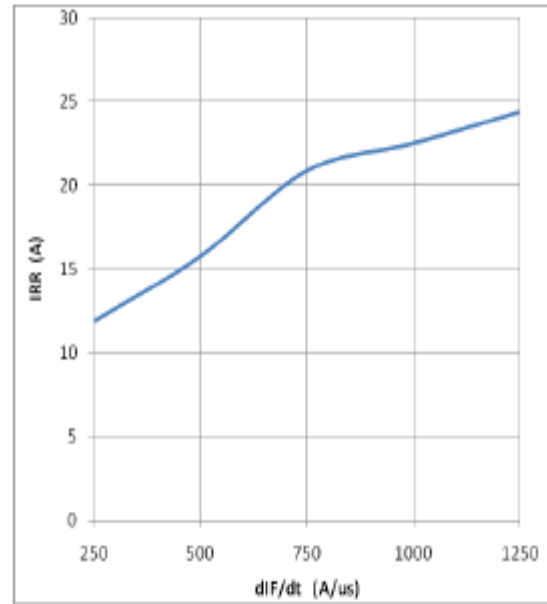


Figure14: typical diode IRR VS. dIF/dt  
VCC=600V, VGE=15V

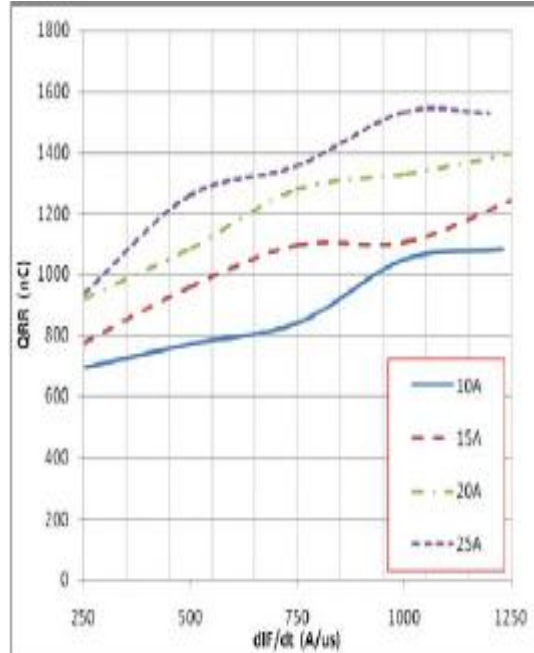


Figure15: typical diode QRR VS. dIF/dt  
VCC=600V, VGE=15V

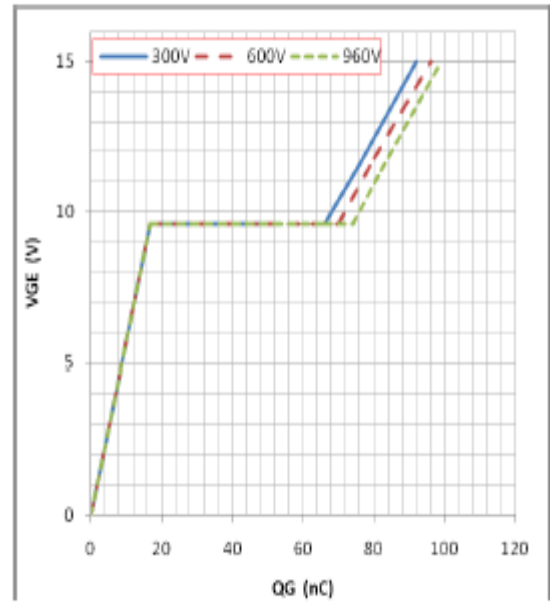
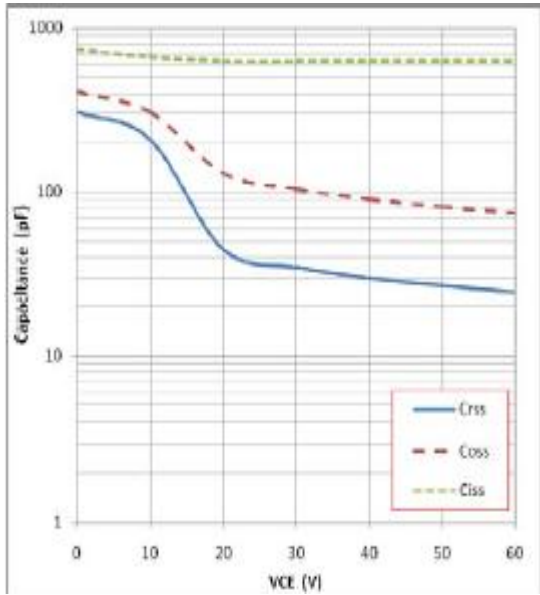


Figure17:typical capacitance VS. VCE,VGE=0V,f=100kHz    Figure18:typical gate charge VS. VGE,IC=25A

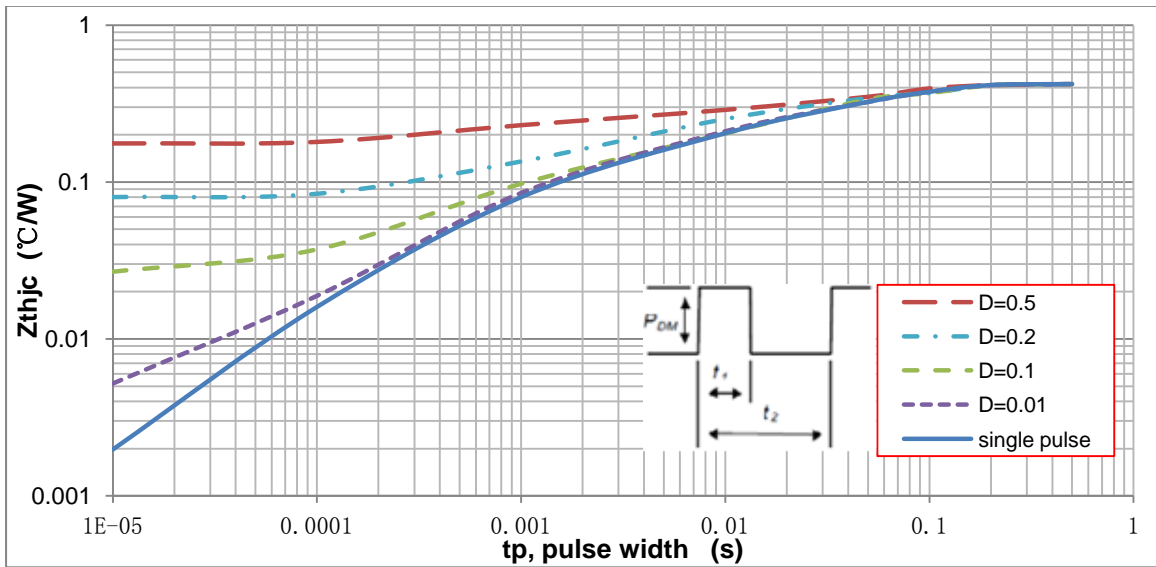
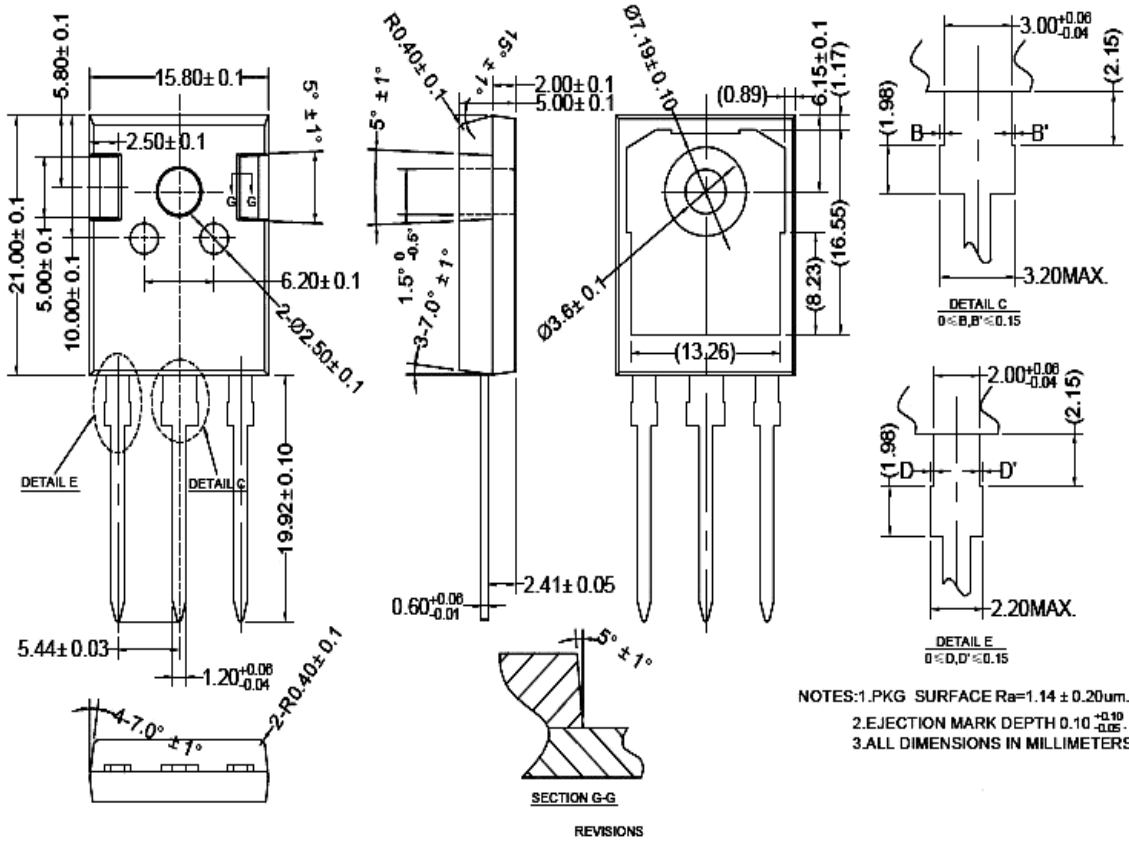


Figure19:normalised transient thermal impedance, junction-to-case

Note1.Duty factor  $D=t_1/t_2$ ;    Note2:peak  $T_J=P_{DM} \times Z_{thjc}+T_C$

TO247 PACKAGE OUTLINE



NOTES: 1. PKG SURFACE Ra=1.14 ± 0.20um.  
2. EJECTION MARK DEPTH 0.10 <sup>+0.10</sup>/<sub>-0.05</sub>.  
3. ALL DIMENSIONS IN MILLIMETERS.

0 ≤ D, D' ≤ 0.15

NOTES: 1. PKG SURFACE Ra=1.14 ± 0.20um.  
2. EJECTION MARK DEPTH 0.10 <sup>+0.10</sup>/<sub>-0.05</sub>.  
3. ALL DIMENSIONS IN MILLIMETERS.

公差标注	公差值	表面粗糙度
0	±0.2	Ra3.2~6.3
0.0	±0.1	Ra1.6~3.2
0.00	±0.01	Ra0.8~1.6
0.000	±0.005	Ra0.4~0.8
0.0000	±0.002	Ra0.2~0.4



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